SCLS323G – MARCH 1996 – REVISED JANUARY 2000

- *EPIC*<sup>™</sup> (Enhanced-Performance Implanted CMOS) Process
- Operating Range 2-V to 5.5-V V<sub>CC</sub>
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Package Options Include Plastic Small-Outline Transistor (DBV, DCK) Packages

#### description

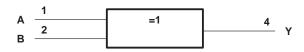
The SN74AHC1G86 is a single 2-input exclusive-OR gate. The device performs the Boolean function  $Y = A \oplus B$  or  $Y = \overline{AB} + A\overline{B}$  in positive logic.

A common application is as a true/complement element. If one of the inputs is low, the other input is reproduced in true form at the output. If one of the inputs is high, the signal on the other input is reproduced inverted at the output.

The SN74AHC1G86 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE								
INPUTS		OUTPUT						
Α	В	Y						
L	L	L						
L	Н	н						
н	L	н						
н	Н	L						

### logic symbol<sup>†</sup>



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



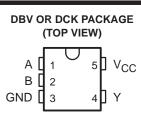
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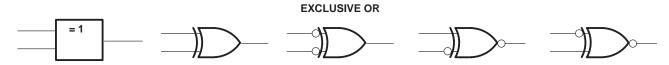
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SCLS323G - MARCH 1996 - REVISED JANUARY 2000

#### exclusive-OR logic

An exclusive-OR gate has many applications, some of which can be represented better by alternative logic symbols.



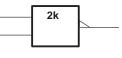
These are five equivalent exclusive-OR symbols valid for an SN74AHC1G86 gate in positive logic; negation may be shown at any two ports.

#### LOGIC-IDENTITY ELEMENT

The output is active (low) if all inputs stand at the same

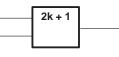
logic level (i.e., A = B).

#### EVEN-PARITY ELEMENT



The output is active (low) if an even number of inputs (i.e., 0 or 2) are active.

#### ODD-PARITY ELEMENT



The output is active (high) if an odd number of inputs (i.e., only 1 of the 2) are active.

### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage range, V <sub>CC</sub>	–0.5 V to 7 V
Input voltage range, VI (see Note 1)	
Output voltage range, V <sub>O</sub> (see Note 1)0.5	5 V to V <sub>CC</sub> + 0.5 V
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0)	–20 mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CC}$ )	±20 mA
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$	±25 mA
Continuous current through V <sub>CC</sub> or GND	±50 mA
Package thermal impedance, $\theta_{JA}$ (see Note 2): DBV package	347°C/W
DCK package	389°C/W
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51.



SCLS323G - MARCH 1996 - REVISED JANUARY 2000

## recommended operating conditions (see Note 3)

			MIN	MAX	UNIT
VCC	Supply voltage		2	5.5	V
		$V_{CC} = 2 V$	1.5		
VIH	High-level input voltage	$V_{CC} = 3 V$	2.1		V
		V <sub>CC</sub> = 5.5 V	3.85		
	Voc = 2 VLow-level input voltageVcc = 3 VVcc = 5.5 V	$V_{CC} = 2 V$		0.5	
VIL		$V_{CC} = 3 V$		0.9	V
		V <sub>CC</sub> = 5.5 V		1.65	
VI	Input voltage		0	5.5	V
VO	Output voltage		0	VCC	V
		$V_{CC} = 2 V$		-50	μΑ
IOH	High-level output current	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		-4	A
		$V_{CC} = 5 V \pm 0.5 V$		-8	mA
		$V_{CC} = 2 V$		50	μA
IOL	Low-level output current $V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$ $V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		4	A
		$V_{CC} = 5 V \pm 0.5 V$		8	mA
A+/A\.	Input transition rise or fall rate	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		100	ns/V
$\Delta t / \Delta v$	Input transition rise or fall rate $V_{CC} = 5 V \pm 0.5 V$			20	115/ V
TA	Operating free-air temperature		-40	85	°C

NOTE 3: All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	v <sub>cc</sub> -	T <sub>A</sub> = 25°C				MAY		
PARAMETER			MIN	TYP	MAX		WAA	UNIT	
		2 V	1.9	2		1.9			
	I <sub>OH</sub> = -50 μA	3 V	2.9	3		2.9			
VOH		4.5 V	4.4	4.5		4.4		V	
	$I_{OH} = -4 \text{ mA}$	3 V	2.58			2.48			
	I <sub>OH</sub> = -8 mA	MIN TYP MAX MIN MAX UNI $2 \vee$ 1.9 2 1.9							
	I <sub>OL</sub> = 50 μA	2 V			0.1		0.1	V	
		3 V			0.1		0.1		
VOL		4.5 V			0.1		0.1		
	$I_{OL} = 4 \text{ mA}$	3 V			0.36		0.44		
	I <sub>OL</sub> = 8 mA	4.5 V			0.36		0.44		
l	$V_{I} = V_{CC} \text{ or } GND$	0 V to 5.5 V			±0.1		±1	μA	
ICC	$V_{I} = V_{CC} \text{ or } GND, \qquad I_{O} = 0$	5.5 V			1		10	μA	
Ci	$V_I = V_{CC}$ or GND	5 V		4	10		10	pF	



SCLS323G - MARCH 1996 - REVISED JANUARY 2000

# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 3.3 V $\pm$ 0.3 V (unless otherwise noted) (see Figure 1)

Γ	PARAMETER	FROM	TO (OUTPUT)	LOAD CAPACITANCE	T <sub>A</sub> = 25°C			MIN	МАХ	UNIT	
		(INPUT)			MIN	TYP	MAX		WAX	UNIT	
Γ	<sup>t</sup> PLH	A or P	Y	V	V 0: 15 m		7	11	1	13	
Γ	<sup>t</sup> PHL	A or B		C <sub>L</sub> = 15 pF		7	11	1	13	ns	
Γ	<sup>t</sup> PLH	A an D	Y	0. 50 - 5		9.5	14.5	1	16.5		
Γ	<sup>t</sup> PHL	A or B		Ŷ	Y $C_{L} = 50 \text{ pF}$		9.5	14.5	1	16.5	ns

# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

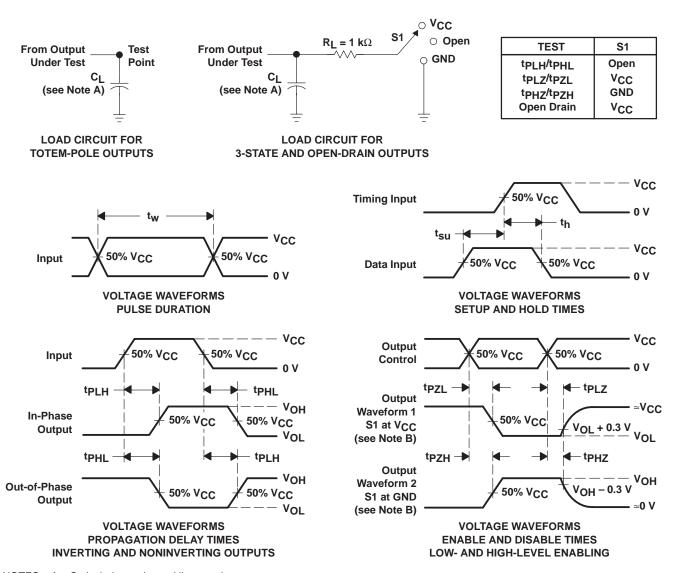
PARAMETER	FROM	то	LOAD	T <sub>A</sub> = 25°C			MIN	мах	UNIT
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX		IVIAA	UNIT
<sup>t</sup> PLH	A an D	Y	C <sub>L</sub> = 15 pF		4.8	6.8	1	8	
<sup>t</sup> PHL	A or B				4.8	6.8	1	8	ns
<sup>t</sup> PLH	A or B	Y	C <sub>L</sub> = 50 pF		6.3	8.8	1	10	20
<sup>t</sup> PHL	AOIB				6.3	8.8	1	10	ns

# operating characteristics, $V_{CC}$ = 5 V, $T_A$ = 25°C

PARAMETER		TEST CO	ONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance	No load,	f = 1 MHz	18	pF



SCLS323G - MARCH 1996 - REVISED JANUARY 2000



PARAMETER MEASUREMENT INFORMATION

### NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>f</sub>  $\leq$  3 ns, t<sub>f</sub>  $\leq$  3 ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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